## Application/Control No. Applicant(s)/Patent Under Reexamination 10/729,991 NAM ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Chen-Wen Jiang 3744

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,122,801 A	09-2000	Reichert et al.	16/284
	В	US-			
	С	US-			
	۵	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	KR 2002004462 A	01-2002	Korea, Republic	JUNG et al.	F25D 23/02
	0					
	Р					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.